

1<sup>st</sup> International Workshop on

## Dependability Issues in Deep-submicron Technologies

May 26<sup>th</sup>-27<sup>th</sup>, 2011, Trondheim, Norway

Fringe Workshop to 

### Call for Papers

Deep-submicron technologies are the enabling factor for developing innovative devices and systems, embedding ever-growing computing capabilities. At the same time deep-submicron technologies are challenging reliability engineers as a number of reliability issues are emerging that must be controlled in order to develop successful technologies and products: fault models different from the traditional stuck-at have to be considered during manufacturing tests to improve test quality, and new phenomena have to be mastered to predict the lifetime of systems and to prevent products from failing both temporarily and permanently. The request for high dependability in deep-submicron technologies is coming from a wide spectrum of applications, spanning from the consumer domain to the automotive domain, eventually reaching the high-reliability domain like avionic and space markets that, although very different, share the same need for high performance computing.

The purpose of this workshop is to bring together experts from the academia and the industry to illustrate all the aspects of dependability issues in deep-submicron technologies, covering from the technological aspects that are essential to understand the fault models for deep-submicron technologies, to architectural aspects needed to design dependable systems based on deep-submicron technologies.

Interested contributors are invited to submit a paper of no more than 4 pages with the description of their work, including references and figures. To provide a basis for fruitful discussions, authors of accepted abstracts will be asked to give a presentation at the workshop, which will be limited to 15 minutes plus 5 minutes of discussion. The accepted papers will be available at the workshop website.

After the workshop, authors of accepted papers will be asked to submit an extended version of their work for a second round of review to a special issue of Microelectronics Journal published by Elsevier dedicated to "Dependability Issues in Deep-submicron Technologies".

### Submission

Workshops papers (up to 4 pages, IEEE double column format) have to be submitted by March 7<sup>th</sup>, 2011, by sending a pdf file via e-mail to the address: [massimo.violante@polito.it](mailto:massimo.violante@polito.it).

The workshop paper should include the title and list of authors with their affiliation and email contact. Please indicate DDT11 in the subject of the email.

### Deadlines

Workshop paper submission: **March 7<sup>th</sup>, 2011**

Notification of acceptance: April 12<sup>th</sup>, 2011

Camera-Ready: May 10<sup>th</sup>, 2011

DDT'11: May 26<sup>th</sup>-27<sup>th</sup>, 2011

### Organizers

Massimo Violante, Politecnico di Torino, Italy

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